

Test Your Dream !

DM2500Plus/DM3500

Wafer Level Test & Burn-In Test System

DM2500Plus/3500, Wafer Level Test & Burn-In Tester, provides you the most cost-effective, high-performance for patterned wafer. It can execute Function Test and Post Analysis by embedded Fail Memory.

- Yield improvement
(SDRAM, SRAM, DDR, FLASH, MCP, DDP and SIP)
- Reduction of Package Level Burn-in time
- Endurance test function for Flash-Memory
- Wafer Business & KGD Products(Special Circuit needed)
- PCI 32bits Bus Interface
- DC, VS Auto Performance Check Function
- Self-diagnostic Function
- Fail Memory Function (Option)



- DM2500Plus : 20MHz 144DUT/Station 2Stations/System(Single ALPG)
- DM3500 : 20MHz 144DUT/Station 2Stations/System(Dual ALPG)

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